Applicant(s)/Patent Under Reexamination Application/Control No. 09/757,006 GEIER ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Le Nguyen 2174

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,452,609	09-2002	Katinsky et al.	715/716
	В	US-			
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NON-PATENT DOCUMENTS

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